

<b>Notice of References Cited</b>	Application/Control No. 10/581,059		Applicant(s)/Patent Under Reexamination AIZU ET AL.	
	Examiner ZEWDU BEYEN		Art Unit 2419	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,145,084 A	11-2000	Zuili et al.	726/3
*	B	US-6,199,164 B1	03-2001	Nishimoto et al.	726/2
*	C	US-2002/0124053 A1	09-2002	Adams et al.	709/216
*	D	US-2002/0136206 A1	09-2002	Gallant et al.	370/352
*	E	US-2003/0028639 A1	02-2003	Yamamoto et al.	709/225
*	F	US-2003/0061380 A1	03-2003	Saito et al.	709/238
*	G	US-6,532,241 B1	03-2003	Ferguson et al.	370/469
*	H	US-2003/0115327 A1	06-2003	Kokado et al.	709/225
*	I	US-2003/0140121 A1	07-2003	Adams, Jeffrey B.	709/219
*	J	US-2004/0170267 A1	09-2004	Seligmann, Doree Duncan	379/211.01
*	K	US-6,798,786 B1	09-2004	Lo et al.	370/468
*	L	US-6,819,663 B2	11-2004	Komuro, Toshinao	370/352
*	M	US-2004/0255032 A1	12-2004	Danieli, Damon V.	709/229

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**

Application/Control No.

10/581,059

Applicant(s)/Patent Under  
Reexamination  
AIZU ET AL.

Examiner

ZEWDU BEYEN

Art Unit

2419

Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0108520 A1	05-2005	Yamamoto et al.	713/155
*	B	US-2005/0210148 A1	09-2005	Kato et al.	709/244
*	C	US-2005/0216595 A1	09-2005	Miyata et al.	709/227
*	D	US-2006/0009213 A1	01-2006	Stumolo et al.	455/426.1
*	E	US-7,017,050 B2	03-2006	Dalton et al.	726/5
*	F	US-2006/0077957 A1	04-2006	Reddy et al.	370/352
*	G	US-7,076,554 B1	07-2006	Kobayashi, Yoshikazu	709/227
*	H	US-7,103,663 B2	09-2006	Inoue et al.	709/225
*	I	US-7,170,857 B2	01-2007	Stephens et al.	370/230
*	J	US-2007/0047523 A1	03-2007	Jiang, John Yue Jun	370/352
*	K	US-7,233,997 B1	06-2007	Leveridge et al.	709/229
*	L	US-2007/0286389 A1	12-2007	Hyerle et al.	379/207.01
*	M	US-7,349,369 B2	03-2008	Tsirtsis et al.	370/328

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/581,059		Applicant(s)/Patent Under Reexamination AIZU ET AL.	
	Examiner ZEWDU BEYEN		Art Unit 2419	Page 3 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,356,601 B1	04-2008	Clymer et al.	709/229
*	B	US-7,353,282 B2	04-2008	Nichols et al.	709/229
*	C	US-7,437,732 B1	10-2008	Boydston et al.	719/313
*	D	US-7,437,752 B2	10-2008	Heard et al.	726/1
*	E	US-7,440,456 B2	10-2008	Furukawa et al.	370/392
*	F	US-7,454,195 B2	11-2008	Lewis et al.	455/412.1
*	G	US-2009/0077602 A1	03-2009	O'Neil, Joseph Thomas	725/109
*	H	US-7,509,379 B2	03-2009	Degraeve, Michel	709/206
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.